Resource Summary Report

Generated by dkNET on Apr 23, 2025

FEI Helios G4 UX

RRID:SCR_021773
Type: Tool

Proper Citation

FEI Helios G4 UX (RRID:SCR_021773)

Resource Information

URL: http://www.mcpf.hkust.edu.hk/service.php?id=PE022

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Description: Dual beam FIB/FESEM system, containing both focused Ga plus ion beam and ultra high resolution field emission scanning electron column and their combined use. Dual beam focused ion beam scanning electron microscope for nanofabrication.

Synonyms: Helios G4 UX

Resource Type: instrument resource

Keywords: FIB, SEM, nanofabrication, dual beam, focused ion beam, scanning electron microscope, USEDit

Funding:

Availability: Commercially available

Resource Name: FEI Helios G4 UX

Resource ID: SCR_021773

Alternate IDs: Model_Number_FEI Helios G4 UX

Record Creation Time: 20220129T080357+0000

Record Last Update: 20250420T015133+0000

Ratings and Alerts

No rating or validation information has been found for FEI Helios G4 UX.

No alerts have been found for FEI Helios G4 UX.

Data and Source Information

Source: SciCrunch Registry

Usage and Citation Metrics

We found 1 mentions in open access literature.

Listed below are recent publications. The full list is available at dkNET.

Ichikawa T, et al. (2023) Protocol for live imaging of intracellular nanoscale structures using atomic force microscopy with nanoneedle probes. STAR protocols, 4(3), 102468.